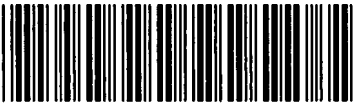


<b>Search Notes</b>  	<b>Application/Control No.</b>  10707003	<b>Applicant(s)/Patent Under Reexamination</b>  BENTWICH, ITZHAK
	<b>Examiner</b>  Shin, Dana	<b>Art Unit</b>  1635

SEARCHED			
Class	Subclass	Date	Examiner
536	23.1, 24.5	6-27-07	DS
435	6	6-27-07	DS

SEARCH NOTES		
Search Notes	Date	Examiner
STIC - SEQ ID NOs: 3588 (Score over length) search results available on SCORE	6-26-07	DS
EAST - attached	6-27-07	DS
PALM - inventor name search	6-27-07	DS

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner